Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10736698	CHEN ET AL.
Examiner	Art Unit
GERMAN VIANA DI PRISCO	2617

SEARCHED					
Class	Subclass	Date	Examiner		
370	328	4/3/2008	GV		

SEARCH NOTES				
Search Notes	Date	Examiner		
EAST Image and keyword search in USPAT, US-PGPUB, DERWENT,	4/3/2008	GV		
EPO, JPO, and IBM_TDB (see attached search strategy)				
Inventor name and Assignee search in PALM ExPO and EAST	4/3/2008	GV		
EPO Database(http://ep.espacenet.com)	4/3/2008	GV		
Consulted with Rafael Perez-Gutierrez	4/3/2008	GV		

INTERFERENCE SEARCH					
Class	Subclass	Date	Examiner		

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